Annex A: System Check

Tested Model : KM7

Report Number:

WSCT-ANAB-R&E250400030A-SARR

Measurement Report for Device, , , UID 0 -, Channel 0 (750.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

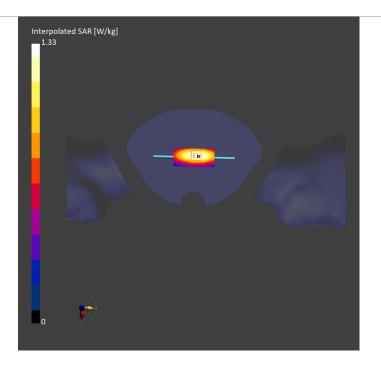
Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	750.000,	9.16	0.885	43.9
Head Simulating Liquid			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup			Measurement Result	S	
	Area Scan	Zoom Scan		Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0	Date	2025-04-23	2025-04-23
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5	psSAR1g [W/kg]	0.853	0.858
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	0.573	0.570
Graded Grid	N/A	Yes	Power Drift [dB]	0.00	0.01
Grading Ratio	N/A	1.5	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		86.4
			Dist 3dB Peak [mm]		22.1



Measurement Report for Device, , , UID 0 -, Channel 0 (835.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

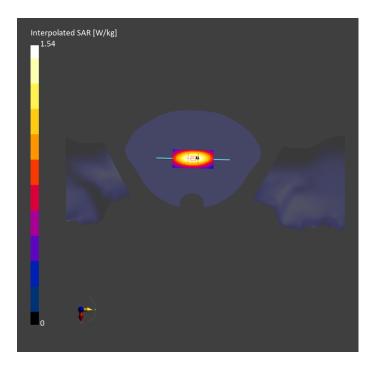
Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	835.000,	8.89	0.914	416
Head Simulating Liquid			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup			Measurement Result	S	
	Area Scan	Zoom Scan		Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0	Date	2025-04-26	2025-04-26
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5	psSAR1g [W/kg]	0.993	0.994
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	0.653	0.655
Graded Grid	N/A	Yes	Power Drift [dB]	0.01	0.02
Grading Ratio	N/A	1.5	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		86.2
			Dist 3dB Peak [mm]		16.4



Measurement Report for Device, , , UID 0 -, Channel 0 (1750.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

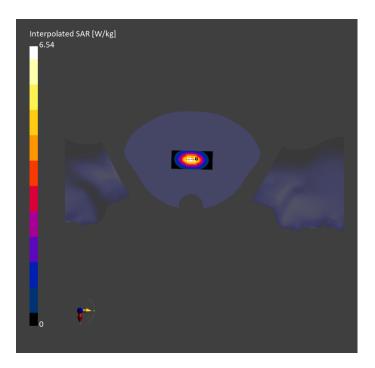
Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	1750.000,	7.6	1.34	41.9
Head Simulating Liquid			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup			Measurement Result	S	
	Area Scan	Zoom Scan		Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0	Date	2025-04-30	2025-04-30
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5	psSAR1g [W/kg]	3.62	3.62
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	1.92	1.95
Graded Grid	N/A	Yes	Power Drift [dB]	0.01	0.00
Grading Ratio	N/A	1.5	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		83.2
			Dist 3dB Peak [mm]		10.8



Measurement Report for Device, , , UID 0 -, Channel 0 (1900.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

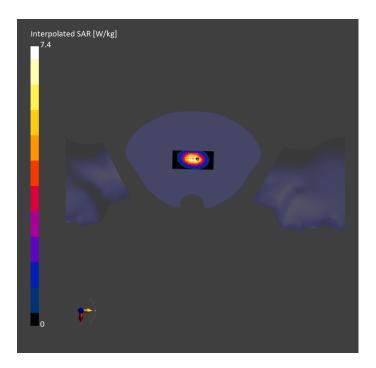
Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	1900.000,	7.33	1.44	41.7
Head Simulating Liquid			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup			Measurement Result	S	
	Area Scan	Zoom Scan		Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0	Date	2025-05-06	2025-05-06
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5	psSAR1g [W/kg]	4.01	4.04
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	2.10	2.11
Graded Grid	N/A	Yes	Power Drift [dB]	-0.01	0.02
Grading Ratio	N/A	1.5	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		83.0
			Dist 3dB Peak [mm]		9.6



Measurement Report for Device, , , UID 0 -, Channel 0 (2550.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

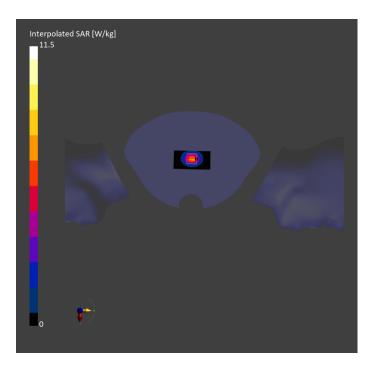
Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	2550.000,	6.94	1.90	40.8
Head Simulating Liquid			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup			Measurement Result	S	
	Area Scan	Zoom Scan		Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0	Date	2025-05-13	2025-05-13
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5	psSAR1g [W/kg]	5.48	5.58
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	2.53	2.56
Graded Grid	N/A	Yes	Power Drift [dB]	0.00	0.01
Grading Ratio	N/A	1.5	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		80.5
			Dist 3dB Peak [mm]		9.0



Measurement Report for Device, , , UID 0 -, Channel 0 (5200.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

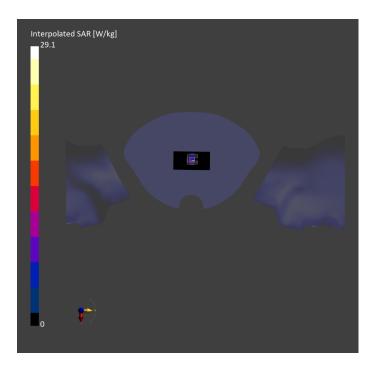
Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	5200.000,	5.34	4.54	36.3
Head Simulating Liquid			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup	Measurement Results				
-	Area Scan	Zoom Scan		Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0	Date	2025-05-19	2025-05-19
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4	psSAR1g [W/kg]	6.41	7.17
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	1.91	2.07
Graded Grid	N/A	Yes	Power Drift [dB]	0.02	0.01
Grading Ratio	N/A	1.4	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		62.3
			Dist 3dB Peak [mm]		7.2



Measurement Report for Device, , , UID 0 -, Channel 0 (5300.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

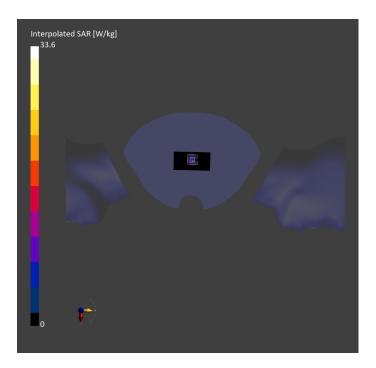
Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	5300.000,	5.28	4.65	36.2
Head Simulating Liquid			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup	Measurement Results				
	Area Scan	Zoom Scan		Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0	Date	2025-05-20	2025-05-20
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4	psSAR1g [W/kg]	7.15	8.08
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	2.09	2.31
Graded Grid	N/A	Yes	Power Drift [dB]	0.01	0.08
Grading Ratio	N/A	1.4	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		61.4
			Dist 3dB Peak [mm]		7.2



Measurement Report for Device, , , UID 0 -, Channel 0 (5500.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

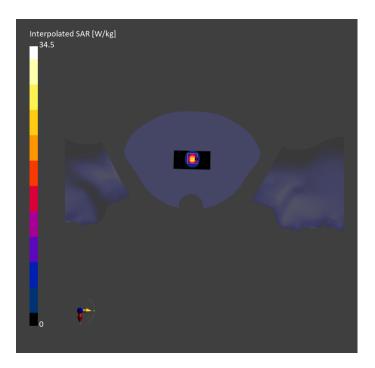
Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	5500.000,	4.87	4.88	35.8
Head Simulating			0	0			
Liquid							

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup	Measurement Results				
	Area Scan	Zoom Scan		Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0	Date	2025-05-22	2025-05-22
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4	psSAR1g [W/kg]	6.98	7.90
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	2.03	2.25
Graded Grid	N/A	Yes	Power Drift [dB]	0.03	0.02
Grading Ratio	N/A	1.4	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		59.5
			Dist 3dB Peak [mm]		7.2



Measurement Report for Device, , , UID 0 -, Channel 0 (5600.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

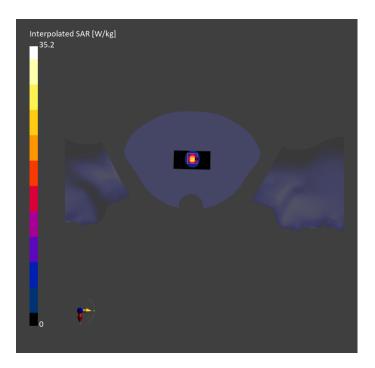
Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	5600.000,	4.87	5.00	35.6
Head Simulating Liquid			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup			Measurement Result	s	
	Area Scan	Zoom Scan		Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0	Date	2025-05-24	2025-05-24
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4	psSAR1g [W/kg]	7.00	7.87
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	2.04	2.24
Graded Grid	N/A	Yes	Power Drift [dB]	0.02	0.01
Grading Ratio	N/A	1.4	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		58.4
			Dist 3dB Peak [mm]		7.2



Measurement Report for Device, , , UID 0 -, Channel 0 (5800.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	5800.000,	4.84	5.23	35.3
Head Simulating Liquid			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup	Measurement Results				
-	Area Scan	Zoom Scan		Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0	Date	2025-05-25	2025-05-25
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4	psSAR1g [W/kg]	6.76	7.76
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	2.00	2.20
Graded Grid	N/A	Yes	Power Drift [dB]	0.01	0.01
Grading Ratio	N/A	1.4	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		56.9
			Dist 3dB Peak [mm]		7.6

